Enhancement of superconductivity near the pressure-induced semiconductor-metal transition in BiS_2 -based superconductors $LnO_{0.5}F_{0.5}BiS_2$ (Ln = La, Ce, Pr, Nd)

C T Wolowiec^{1,2}, B D White^{1,2}, I Jeon^{1,2,3}, D Yazici^{1,2}, K Huang^{1,2,3} and M B Maple^{1,2,3}

- $^{\rm 1}$ Department of Physics, University of California, San Diego, La Jolla, California 92093, USA
- ² Center for Advanced Nanoscience, University of California, San Diego, La Jolla, California 92093, USA
- ³ Materials Science and Engineering Program, University of California, San Diego, La Jolla, California 92093, USA

E-mail: mbmaple@.ucsd

Abstract. Measurements of electrical resistivity were performed between 3 and 300 K at various pressures up to 2.8 GPa on the BiS₂-based superconductors $LnO_{0.5}F_{0.5}BiS_2$ (Ln = Pr, Nd). At lower pressures, $PrO_{0.5}F_{0.5}BiS_2$ and $NdO_{0.5}F_{0.5}BiS_2$ exhibit superconductivity with critical temperatures T_c of 3.5 and 3.9 K, respectively. As pressure is increased, both compounds undergo a transition at a pressure $P_{\rm t}$ from a low $T_{\rm c}$ superconducting phase to a high $T_{\rm c}$ superconducting phase in which T_c reaches maximum values of 7.6 and 6.4 K for $PrO_{0.5}F_{0.5}BiS_2$ and NdO_{0.5}F_{0.5}BiS₂, respectively. The pressure-induced transition is characterized by a rapid increase in T_c within a small range in pressure of ~ 0.3 GPa for both compounds. In the normal state of $PrO_{0.5}F_{0.5}BiS_2$, the transition pressure P_t correlates with the pressure where the suppression of semiconducting behaviour saturates. In the normal state of $NdO_{0.5}F_{0.5}BiS_2$, P_t is coincident with a semiconductor-metal transition. This behaviour is similar to the results recently reported for the $LnO_{0.5}F_{0.5}BiS_2$ (Ln = La, Ce) compounds. We observe that $P_{\rm t}$ and the size of the jump in $T_{\rm c}$ between the two superconducting phases both scale with the lanthanide element in $LnO_{0.5}F_{0.5}BiS_2$ (Ln= La, Ce, Pr, Nd).

PACS numbers: 61.50.Ks, 74.25.F-, 74.62.Bf, 74.62.Fj, 74.70.Dd

Submitted to: J. Phys.: Condens. Matter

1. Introduction

The recent discovery of the BiS₂-based superconductor Bi₄O₄S₃ by Mizuguchi *et al.* [1, 2] with a superconducting critical temperature T_c^{onset} of 8.6 K has generated much interest in a new family of BiS₂-based superconductors. The members of the class of novel BiS₂-based superconductors have layered crystal structures that consist of superconducting BiS₂ layers separated by blocking layers which act as charge reservoirs that dope the BiS₂ layers with charge carriers.[1] Experimental efforts on the BiS₂-based materials have focused on increasing the charge carrier concentration via chemical substitution within the blocking layer [3, 4, 5, 6, 7, 8, 9, 10, 11, 12] as well as through a reduction of the unit cell volume via the application of an external pressure.[13, 14, 15, 16]

Recent studies of the BiS₂-based compounds involving chemical substitution within the blocking layers have lead to the discovery of the related superconductors $LnO_{0.5}F_{0.5}BiS_2$ (Ln=La, Ce, Pr, Nd, Yb).[4, 8, 9, 10, 11, 15] The compound $LaO_{0.5}F_{0.5}BiS_2$, synthesized under high pressure, has been reported by Mizuguchi *et al.* to have a T_c of 10.6 K which exceeds that of $Bi_4O_4S_3$.[9] In addition, the compounds with Ln=Ce, Pr, Nd, and Yb exhibit T_c^{onset} values of ~ 3.0 , 5.6, 4.3, and 5.3 K, respectively.[4, 8, 10, 11] More recent work demonstrates that chemical substitution of the tetravalent ions Th^{+4} , Hf^{+4} , Zr^{+4} and Ti^{+4} for trivalent La^{+3} in $LaOBiS_2$ increases the charge-carrier density and induces superconductivity.[12]

Measurements of the pressure dependence of the electrical resistivity ρ and the superconducting critical temperature $T_{\rm c}$ have also recently been reported for several of these new compounds.[13, 14, 15, 16] In this paper, we report the temperature dependence of the electrical resistivity ρ from 3 to 300 K for the $LnO_{0.5}F_{0.5}BiS_2$ (Ln=Pr,Nd) compounds under applied quasi-hydrostatic pressure up to \sim 2.8 GPa. Both compounds exhibit the same qualitative evolution of $T_{\rm c}$ in which they undergo a pressure-induced transition at $P_{\rm t}$ from a low $T_{\rm c}$ superconducting phase to a high $T_{\rm c}$ superconducting phase. This transition region is characterized by a rapid increase of $T_{\rm c}$ in a narrow range of pressure \sim 0.3 GPa. In the high $T_{\rm c}$ phase at \sim 2.5 GPa, we observed a maximum $T_{\rm c}$ of 7.6 K for $PrO_{0.5}F_{0.5}BiS_2$ and 6.4 K for $NdO_{0.5}F_{0.5}BiS_2$. In the normal state of both materials, there is a significant suppression of semiconducting behaviour with pressure which is continuous up to the pressure $P_{\rm t}$. A rapid increase of the charge carrier density is inferred from both the suppression of the semiconducting behaviour and the rapid increase of $T_{\rm c}$ in this region.[17]

The pressure dependence of ρ and the evolution of T_c reported in this article for the $LnO_{0.5}F_{0.5}BiS_2$ (Ln=Pr,Nd) compounds are qualitatively similar to the behaviour we recently reported for the $LnO_{0.5}F_{0.5}BiS_2$ (Ln=La,Ce) compounds.[14] For the four BiS_2 -based layered superconductors, $LnO_{0.5}F_{0.5}BiS_2$ (Ln=La,Ce,Pr,Nd), the transition pressure P_t and the size of the "jump" in T_c between the two superconducting phases both scale with the lanthanide element Ln; specifically, as the atomic number of Ln increases, P_t increases while the "jump" in T_c decreases.

2. Experimental section

Polycrystalline samples of $LnO_{1-x}F_xBiS_2$ (Ln = Pr, Nd) with x = 0.5 were prepared by solid-state reaction using powders of Pr_2O_3 (99.9%), PrF_3 (99.9%), Pr_2S_3 (99.9%), and Bi_2S_3 (99.9%) for $PrO_{1-x}F_xBiS_2$, and powders of Nd_2O_3 (99.9%), NdF_3 (99.9%), Nd_2S_3 (99.9%), and Bi_2S_3 (99.9%) for $NdO_{1-x}F_xBiS_2$. Bi_2S_3 precursor powder was prepared in an evacuated quartz tube by reacting Bi (99.99%) and S (99.9%) at 500°C for 10 hours. The Ln_2S_3 (Ln = Pr, Nd) precursor powders were prepared in an evacuated quartz tube by reacting chunks of Pr and Nd with S grains at 800°C for 10 hours. The starting materials with nominal composition $LnO_{0.5}F_{0.5}BiS_2$ (Ln = Pr, Nd) were weighed, thoroughly mixed, pressed into pellets, sealed in evacuated quartz tubes, and annealed at 800°C for 48 hours. The products were ground, mixed for homogenization, pressed into pellets, and annealed again in evacuated quartz tubes at 800°C for 48 hours. This last step was repeated again to promote phase homogeneity. X-ray powder diffraction measurements (not shown) were made using an X-ray diffractometer with a Cu K_{α} source to assess phase purity and to determine the lattice parameters of the $LnO_{0.5}F_{0.5}BiS_2$ (Ln = Pr, Nd) compounds. The main diffraction peaks for the two samples can be well indexed to a tetragonal structure with space group P_4/nmm conforming to the CeOBiS₂ structure. The lattice parameters for $PrO_{0.5}F_{0.5}BiS_2$ were determined to be a=b=4.0192 Å and c = 13.4238 Å, while for NdO_{0.5}F_{0.5}BiS₂ the lattice parameters are a = b = 4.0102 Å and c = 13.4468 Å.[11]

Measurements of $\rho(T)$ under applied pressure were performed up to ~ 2.8 GPa in a clamped piston cylinder pressure cell between ~ 3 K and 300 K in a pumped ⁴He dewar. A 1:1 by volume mixture of n-pentane and isoamyl alcohol was used to provide a quasi-hydrostatic pressure transmitting medium. Annealed Pt leads were affixed to gold-sputtered contact surfaces on each sample with silver epoxy in a standard four-wire configuration. The pressure dependence of T_c for high purity Sn (99.999%) was measured inductively and used as a manometer for the experiments. The pressure was determined by calibrating our T_c data for Sn against data used in [18]. The width of the superconducting transition of the Sn manometer was used as a measure of the error in pressure, which was found to be on the order $\Delta P \sim \pm 0.05$ GPa.

3. Results

Plots of the temperature dependence of the electrical resistivity ρ below 300 K for $PrO_{0.5}F_{0.5}BiS_2$ and $NdO_{0.5}F_{0.5}BiS_2$ at various pressures up to 2.8 GPa are shown in Figure 1 (a) and (b), respectively. Both compounds exhibit semiconducting behaviour at low pressure (indicated by a negative temperature coefficient of resistivity $(d\rho/dT < 0)$). The semiconducting behaviour is strongly suppressed at lower pressures. As pressure is increased, the electrical resistivity ρ of $PrO_{0.5}F_{0.5}BiS_2$ becomes weakly temperature dependent above ~ 1.5 GPa, but remains semiconducting $(d\rho/dT < 0)$. In contrast, the

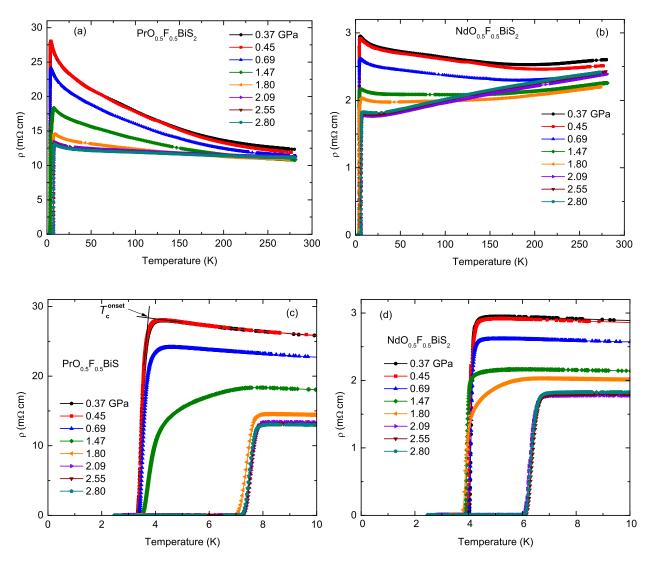


Figure 1: (colour online) (a),(b) Temperature dependence of the electrical resistivity ρ at various pressures for (a) $PrO_{0.5}F_{0.5}BiS_2$ and (b) $NdO_{0.5}F_{0.5}BiS_2$. At lower pressures, both compounds exhibit semiconducting behaviour which is suppressed with increasing pressure. $NdO_{0.5}F_{0.5}BiS_2$ becomes completely metallic at \sim 2 GPa ($d\rho/dT > 0$). (c),(d) Resistive superconducting transition curves for (c) $PrO_{0.5}F_{0.5}BiS_2$ and (d) $NdO_{0.5}F_{0.5}BiS_2$ at various pressures. In $PrO_{0.5}F_{0.5}BiS_2$, T_c increases from 3.5 K to a maximum of 7.6 K while in $NdO_{0.5}F_{0.5}BiS_2$, T_c increases from 3.9 K to a maximum of 6.4 K.

 $NdO_{0.5}F_{0.5}BiS_2$ sample becomes metallic at ~2 GPa (indicated by a positive temperature coefficient of resistivity $(d\rho/dT > 0)$ in Figure 1(b)).

Superconducting transitions for $PrO_{0.5}F_{0.5}BiS_2$ and $NdO_{0.5}F_{0.5}BiS_2$ are displayed in Figure 1(c) and (d), respectively. At lower pressures up to \sim 1 GPa, the superconducting transitions in $PrO_{0.5}F_{0.5}BiS_2$ are grouped near 3.5 K. As pressure is increased, there is a slight broadening of the width of the superconducting transition ΔT_c at \sim 1.5

GPa which is immediately followed by a dramatic increase in $T_{\rm c}$ from ~ 3.9 to 7.4 K in the narrow range ~ 1.5 - 1.8 GPa. Above 1.8 GPa, $T_{\rm c}$ passes through a maximum of 7.6 K at ~ 2.5 GPa and then gradually decreases with increasing pressure. We observed

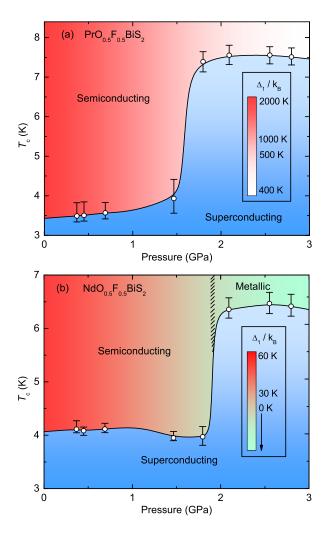


Figure 2: (colour online) Temperature-pressure phase diagrams for (a) $PrO_{0.5}F_{0.5}BiS_2$ and (b) $NdO_{0.5}F_{0.5}BiS_2$ under pressure. Vertical bar lengths represent the transition width ΔT_c and vertical bar caps represent T_c^{onset} (upper) and T_0 (lower). The colour in the semiconducting region represents the energy gap Δ_1 . Values for Δ_1 are indicated in the false colour legend. (b) The green region to the right of the crosshatching corresponds to the metallization of $NdO_{0.5}F_{0.5}BiS_2$ ($\Delta_1 = 0$). The solid black curves are guides to the eye.

similar behaviour in the NdO_{0.5}F_{0.5}BiS₂ compound. Sharp superconducting transitions near 4.0 K were observed at low pressures up to \sim 1.5 GPa. The width $\Delta T_{\rm c}$ of the superconducting transition then appears to broaden near \sim 1.8 GPa. In the small range \sim 1.8 - 2.1 GPa, there is a sizable increase in $T_{\rm c}$ from \sim 3.9 to 6.3 K. In NdO_{0.5}F_{0.5}BiS₂, $T_{\rm c}$ passes through a maximum of 6.4 K at \sim 2.5 GPa and then gradually decreases at higher pressures up to \sim 2.8 GPa, similar to the behaviour observed for PrO_{0.5}F_{0.5}BiS₂.

The temperature-pressure phase diagrams for the $PrO_{0.5}F_{0.5}BiS_2$ and $NdO_{0.5}F_{0.5}BiS_2$ compounds are displayed in Figure 2(a) and (b), respectively. In the superconducting state, both compounds exhibit a low T_c phase which is characterized by a gradual increase in T_c with pressure. In the $PrO_{0.5}F_{0.5}BiS_2$ sample, T_c increases monotonically from 3.5 to 3.9 K at pressures up to ~ 1.5 GPa ($dT_c/dP = 0.40$ K GPa⁻¹). In the $NdO_{0.5}F_{0.5}BiS_2$ sample, there was a non-monotonic decrease in T_c from 4.1 to 3.9 K at pressures up to ~ 1.8 GPa. As pressure is increased, both compounds exhibit a rapid increase in T_c within a narrow range ~ 0.3 GPa. For the $PrO_{0.5}F_{0.5}BiS_2$ compound, T_c increases dramatically from 3.9 to 7.4 K as pressure is increased from ~ 1.5 to 1.8 GPa $(dT_c/dP = 11.7 \text{ K GPa}^{-1})$. In the $NdO_{0.5}F_{0.5}BiS_2$ compound, there is a significant jump in T_c from 3.9 to 6.3 K as pressure is increased from ~ 1.8 to 2.1 GPa ($dT_c/dP =$ 8.0 K GPa⁻¹). Following the rapid increase in T_c , both compounds exhibit a high T_c superconducting phase, in which the evolution of T_c exhibits a domelike behaviour; i.e., $T_{\rm c}$ gradually increases to its maximum value and then slowly decreases with pressure. In the $PrO_{0.5}F_{0.5}BiS_2$ compound, T_c increases to a maximum value of 7.6 K at 2.5 GPa and then steadily decreases with pressure, while in the $NdO_{0.5}F_{0.5}BiS_2$ compound, T_c increases to a maximum T_c of 6.4 K at \sim 2.5 GPa and then decreases slowly with pressure.

In the normal state (above the $T_c(P)$ curves shown in Figure 2), the semiconducting behaviour in both compounds is continuously suppressed with pressure as manifested by the decrease of the energy gap Δ_1 (defined below) with pressure, the values of which are indicated in the false colour legend of Figure 2(a) and (b) for $PrO_{0.5}F_{0.5}BiS_2$ and $NdO_{0.5}F_{0.5}BiS_2$, respectively. The $NdO_{0.5}F_{0.5}BiS_2$ sample exhibits a fully metallic state at \sim 2 GPa (where Δ_1 vanishes), represented by the green region to the right of the crosshatching in Figure 2(b).

From the plot of $\log(\rho)$ vs. P displayed in Figure 3(a), there is a noticeable change in the magnitude of the suppression rate, $\operatorname{dlog}(\rho)/\operatorname{d}P$, for both the $\operatorname{PrO}_{0.5}F_{0.5}\operatorname{BiS}_2$ and $\operatorname{NdO}_{0.5}F_{0.5}\operatorname{BiS}_2$ compounds. The $\rho(P)$ data for $\operatorname{PrO}_{0.5}F_{0.5}\operatorname{BiS}_2$ and $\operatorname{NdO}_{0.5}F_{0.5}\operatorname{BiS}_2$ were taken in the normal state at 8.5 K and 7.5 K, respectively. These temperatures occur just above the onset of the superconducting transition at T_c^{onset} . In both compounds, there is a strong suppression of electrical resistivity up to \sim 2.1 GPa, followed by a weaker suppression at higher pressures. The dotted lines in Figure 3(a) are guides to the eye for the rates of suppression. The change in the suppression rate near 2.1 GPa (emphasized by the vertical arrows in Figure 3(a)) is coincident with $P_{\rm t}$.

The semiconducting behaviour of the $\rho(T)$ data and its rapid suppression with pressure was noted by Kotegawa *et al.* in their study of the LaO_{0.5}F_{0.5}BiS₂ compound synthesized under high pressure.[13] They observed that $\rho(T)$ could be described over two distinct temperature regions by the relation $\rho(T) = \rho_0 e^{\Delta/2k_BT}$ where ρ_0 is a constant and Δ is an energy gap. In a recent paper, we applied this analysis to extract the high and low temperature energy gaps Δ_1 and Δ_2 for the $LnO_{0.5}F_{0.5}BiS_2$ (Ln = La, Ce) compounds.[14] We used the same analysis in the current study to determine the value of the high temperature energy gap Δ_1 for both compounds $LnO_{0.5}F_{0.5}BiS_2$ (Ln

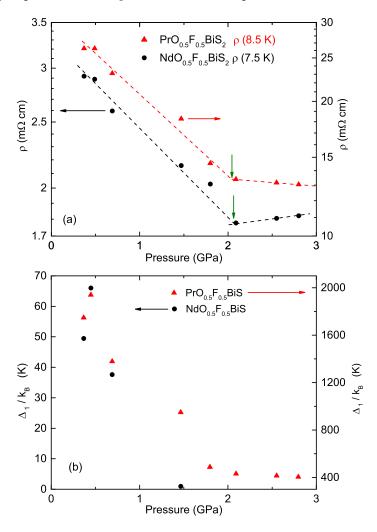


Figure 3: (colour online) (a) Electrical resistivity ρ vs pressure in the normal state (plotted on a log scale). Values of ρ for $PrO_{0.5}F_{0.5}BiS_2$ and $NdO_{0.5}F_{0.5}BiS_2$ were taken at T=8.5 and 7.5 K, respectively. Dotted lines reflect the slopes (suppression rates), and arrows point to changing slopes at \sim 2.1 GPa. The breaks in slope occur at the transition pressure P_t . (b) Energy gap Δ_1 (\sim 100 - 200 K) vs pressure for both compounds. The rate of decrease in Δ_1 with pressure flattens at \sim 2 GPa in both compounds. Above \sim 1.9 GPa, $\Delta_1/k_B=0$ K in $NdO_{0.5}F_{0.5}BiS_2$.

= Pr, Nd). The energy gap Δ_1 in NdO_{0.5}F_{0.5}BiS₂ was determined using the $\rho(T)$ data from the region 100 - 200 K for lower pressures 0.37 - 0.69 GPa and $\rho(T)$ data from the region 20 - 100 K for higher pressures 1.47 - 2.80 GPa. For PrO_{0.5}F_{0.5}BiS₂, the energy gap Δ_1 was extracted using $\rho(T)$ data in the region 200 - 280 K for all pressures up to 2.80 GPa.

The pressure dependence of the energy gap Δ_1 for both compounds is shown in Figure 3(b). The energy gap Δ_1 decreases rapidly with pressure up to \sim 2 GPa. Above \sim 2 GPa, Δ_1 exhibits relatively little pressure dependence. This is consistent with the transition to a weaker suppression rate shown in Figure 3(a) which also sets in at \sim 2 GPa.

In NdO_{0.5}F_{0.5}BiS₂, the energy gap $\Delta_1/k_B = 0$ K above 1.8 GPa. This is consistent with the semiconductor-metal transition near 2 GPa indicated by a positive temperature coefficient of electrical resistivity ($d\rho/dT > 0$) seen in the $\rho(T)$ data shown in Figure 1(b). The rapid decrease in the energy gap Δ_1 for $P < P_t$ in both the $LnO_{0.5}F_{0.5}BiS_2$ (Ln = Pr, Nd) compounds is similar to behaviour observed previously in the $LnO_{0.5}F_{0.5}BiS_2$ (Ln = La, Ce) compounds.[13, 14]

4. Discussion

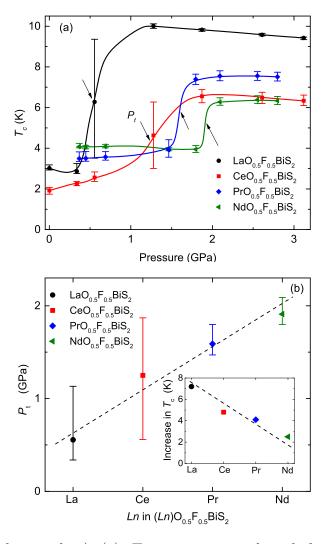


Figure 4: (colour online) (a) T_c vs pressure plotted for the four compounds $LnO_{0.5}F_{0.5}BiS_2$ (Ln = La, Ce, Pr, Nd). The black arrows emphasize the transition pressure P_t which is defined in the text. (b) Transition pressure P_t plotted as a function of Ln in $LnO_{0.5}F_{0.5}BiS_2$. The inset displays the increase in T_c at P_t as a function of Ln. Dashed lines are guides to the eye.

Both the temperature dependence of the electrical resistivity ρ and the evolution

Ln	low $T_{\rm c}$ (K)	max. $T_{\rm c}$ (K)	increase in $T_{\rm c}$ (K)	$P_{\rm t}$ (GPa)
La	2.9	10.1	7.2	0.56
Се	1.9	6.7	4.8	1.25
\Pr	3.5	7.6	4.1	1.59
Nd	3.9	6.4	2.5	1.91
Nu	5.5	0.4	2.0	1.31

Table 1: T_c data for $LnO_{0.5}F_{0.5}BiS_2$ (Ln = La, Ce, Pr, Nd).

of T_c under applied pressure for the $LnO_{0.5}F_{0.5}BiS_2$ (Ln = Pr, Nd) samples reported in section 3 of this paper are markedly similar to the results we recently reported for the $LnO_{0.5}F_{0.5}BiS_2$ (Ln = La, Ce) compounds.[14] As shown in the phase diagrams displayed in Figure 4(a), each of the four compounds $LnO_{0.5}F_{0.5}BiS_2$ (Ln = La, Ce, Pr, Nd) exhibits an abrupt pressure-induced transition from a low T_c superconducting phase at lower pressure to a high T_c superconducting phase at higher pressure.

In the four compounds, the pressure-induced transition observed in the superconducting state is coincident with changes in the suppression of the electrical resistivity ρ in the normal state. The rate of suppression of semiconducting behaviour (Figure 3(a)) and the rate of decrease in the energy gap Δ_1 (Figure 3(b)) both saturate at pressures that correlate with the transition pressure into the high T_c superconducting phase. In the specific case of the NdO_{0.5}F_{0.5}BiS₂ compound, a semiconductor-metal transition occurs at P_t . These changes in the normal state electrical resistivity indicate there may be significant increases in the charge carrier density during the rapid increase in T_c that occurs between the two superconducting phases.[17]

The transition pressures P_t , indicated by the black arrows in the temperature-pressure phase diagrams of Figure 4(a), were defined as the pressure corresponding to the value of T_c at the midpoint between the values of T_c in the low and high T_c phases immediately preceding and following the transition. P_t is plotted as a function of lanthanide element (Ln = La, Ce, Pr, Nd) in $LnO_{0.5}F_{0.5}BiS_2$ in Figure 4(b). There is a clear linear relationship between the increasing atomic number of Ln and an increase in P_t . The magnitude of the "jump" in T_c also scales with the atomic number of the Ln element in $LnO_{0.5}F_{0.5}BiS_2$ as clearly shown in the inset of Figure 4(b). The pressure-induced increase in T_c decreases in magnitude as the atomic number of the lanthanide element increases. The lengths of the vertical bars in Figure 4(b) represent the respective pressure windows over which the transitions from the low T_c phase to the high T_c phase occurred in each of the four compounds. The pressure range over which the transition occurs also decreases with increasing atomic number of Ln in $LnO_{0.5}F_{0.5}BiS_2$. Table 1 contains values of low T_c , maximum T_c , overall increase in T_c (max. T_c - low T_c), and transition pressure P_t , for each compound.

The evolution of T_c with pressure in the low T_c phase has recently been reported for the $LnO_{0.5}F_{0.5}BiS_2$ (Ln = Pr, Nd) compounds in two studies by Selvan *et al.*[15, 16]

For $PrO_{0.5}F_{0.5}BiS_2$, they observed a gradual increase of T_c from 3.7 to 4.7 K with pressure up to \sim 2.2 GPa.[16] For $NdO_{0.5}F_{0.5}BiS_2$, they found a gradual evolution of T_c with pressure from 4.6 to 5.0 K up to a pressure of \sim 1.3 GPa and then down from 5.0 to 4.8 K upon further application of pressure up to \sim 1.8 GPa.[15] In both reports, however, there was no evidence of a transition characterized by a rapid increase in T_c . It is possible that slight variations in the chemical composition of the samples in their studies compared to those studied by us may be responsible for differences in the material's response to applied pressure. Furthermore, the pressure transmitting media used in this study (see section 2) and the transmitting fluid used in their studies [15, 16] may have different properties with regard to pressure gradients that can affect the measured pressure at which a transition occurs.[19] It is also possible that the pressures reached in their studies were lower than the pressure required to induce the transitions that we observed in this report.

5. Concluding remarks

We have observed markedly similar behaviour in the temperature dependence of the normal state electrical resistivity and evolution of the superconducting critical temperature T_c under applied pressure for the two BiS₂-based superconductors $LnO_{0.5}F_{0.5}BiS_2$ (Ln = Pr, Nd). The qualitative behaviour observed for the two compounds in this study is strikingly similar to the results we recently reported for the two BiS₂-based superconductors $LnO_{0.5}F_{0.5}BiS_2$ (Ln = La, Ce).[14] In each of the four compounds $LnO_{0.5}F_{0.5}BiS_2$ (Ln = La, Ce, Pr, Nd), there is a sizable enhancement of T_c in the superconducting state accompanying the suppression of semiconducting behaviour with pressure in the normal state. The suppression of the semiconducting behaviour in the normal state saturates at a critical pressure P_t which corresponds to the pressure where there is a transition between a low T_c superconducting phase and a high T_c superconducting phase. The semiconducting behaviour of the electrical resistivity in the normal state is consistent with an energy gap that is suppressed with pressure in a similar way. In the particular case of the $NdO_{0.5}F_{0.5}BiS_2$ compound, there is a pressure-induced semiconductor-metal transition at $P_t \approx 2$ GPa.

The coincidence of the saturation of the suppression of semiconducting behaviour in the normal state electrical resistivity with the rapid increase in T_c indicates there may be significant increases in the charge carrier density in the vicinity of the pressure-induced transition. We found that the transition pressure P_t (see section 4) increases with increasing atomic number of the lanthanide element (Ln = La, Ce, Pr, Nd) in $LnO_{0.5}F_{0.5}BiS_2$. However, the size of the increase in T_c between the two superconducting phases decreases as lanthanide atomic number increases. The scaling of both the transition pressure P_t and the size of the "jump" in T_c with the atomic number of the lanthanide element suggests that the pressure-induced transition between the two superconducting phases may be a structural transition; however, at present, the precise

mechanism driving the enhancement of $T_{\rm c}$ with pressure is unknown. X-ray diffraction experiments under pressure on the LaO_{0.5}F_{0.5}BiS₂ compound are currently underway to help determine whether the pressure-induced enhancement of $T_{\rm c}$ and the suppression of semiconducting behaviour are related to a structural transition.

Acknowledgments

The authors thank A. J. Friedman for his helpful work in the synthesis of the $LnO_{0.5}F_{0.5}BiS_2$ (Ln=La, Ce, Pr, Nd) compounds. High pressure research at the University of California, San Diego (UCSD) was supported by the National Nuclear Security Administration under the Stewardship Science Academic Alliance Program through the U.S. Department of Energy (DOE) under Grant No. DE-NA0001841. Sample synthesis at UCSD was sponsored by the U.S. Air Force Office of Scientific Research under MURI Grant No. FA9550-09-1-0603. Characterization of samples at ambient pressure was supported by the U.S. DOE Grant No. DE-FG02-04-ER46105.

References

- [1] Mizuguchi Y, Fujihisa H, Gotoh Y, Suzuki K, Usui H, Kuroki K, Demura S, Takano Y, Izawa H and Miura O 2012 *Phys. Rev. B* **86** 220510(R)
- [2] Singh S K, Kumar A, Gahtori B, Kirtan S, Sharma G, Patnaik S and Awana V P S 2012 J. Am. Chem. Soc. 134 16504-7
- [3] Li B, Xing Z W and Huang G Q 2013 Europhys. Lett. 101 47002
- [4] Jha R, Kumar A, Singh S K and Awana V P S 2013 J. Sup. and Novel Maq. 26 499-502
- [5] Jha R, Kumar A, Singh S K and Awana V P S 2013 J. Appl. Phys. 113 056102
- [6] Deguchi K, Mizuguchi Y, Demura S, Hara H, Watanabe T, Denholme S J, Fujioka M, Okazaki H, Ozaki T and Takeya H 2013 Europhys. Lett. 101 17004
- [7] Awana V P S, Kumar A, Jha R, Kumar S, Pal A, Shruti, Saha J and Patnaik S 2013 Solid State Commun. 157 21-23
- [8] Demura S, Mizuguchi Y, Deguchi K, Okazaki H, Hara H, Watanabe T, Denholme S J, Fujioka M, Ozaki T and Fujihisa H 2013 J. Phys. Soc. Japan. 82 033708
- [9] Mizuguchi Y, Demura S, Deguchi K, Takano Y, Fujihisa H, Gotoh Y, Izawa H and Miura O 2012J. Phys. Soc. Japan 81 114725
- [10] Xing J, Li S, Ding X, Yang H and Wen H-H 2012 Phys. Rev. B 86 214518
- [11] Yazici D, Huang K, White B D, Chang A H, Friedman A J and Maple M B 2012 *Philos. Mag.* **93** 673-80
- [12] Yazici D, Huang K, White B D, Jeon I, Burnett V W, Friedman A J, Lum I K, Nallaiyan M, Spagna S and Maple M B 2013 *Phys. Rev. B* 87 174512
- [13] Kotegawa H, Tomita Y, Tou H, Izawa H, Mizuguchi Y, Miura O, Demura S, Deguchi K and Takano Y 2012 J. Phys. Soc. Japan 81 103702
- [14] Wolowiec C T, Yazici D, White B D, Huang K and Maple M B 2013 Phys. Rev. B 88 064503
- [15] Selvan G K, Kanagaraj M, Muthu S E, Jha R, Awana V P S and Arumugam S 2013 Phys. Status Solidi RRL 7 510-3
- [16] Selvan G K, Kanagaraj M, Jha R, Awana V P S and Arumugam S 2013 Preprint arXiv/1307.4877
- [17] Igawa K, Okada H, Takahashi H, Matsuishi S, Kamihara Y, Hirano M, Hosono H, Matsubayashi K and Uwatoko Y 2009 J. Phys. Soc. Japan 78 025001
- [18] Smith T F, Chu C W and Maple M B 1969 Cryogenics 9 53-6

 $[19]\,$ Butch N P, Jeffries J R, Zocco D A and Maple M B 2009 $\it High\ Pressure\ Research\ 29\ 335-43$